

# GD SDR Automatic Gain Control Characterization Testing

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# SCaN Testbed Flight System Overview

- 2 S-band SDRs
- 1 Ka-band SDR
- Ka-band TWTA
- S-band switch network
- Antennas
  - 2 Iow gain S-band antennas
  - 1 L-band GPS antenna
  - Medium gain S-band and Ka-band antenna on antenna pointing subsystem.
- Antenna pointing system
- Flight Computer/Avionics



- Launched on Japanese HTV-3 on July 20, 2012
- Installed on ISS August 7, 2012
- Checkout and Commissioning is in progress

# SCaN Testbed GD SDR Description

- **TDRSS S-band Transponder** 
  - 8 Forward link receive waveform configurations
  - 30 Return link transmit waveform configurations
- 1 Xilinx Virtex II QPro FPGA, 3 M gate
- ColdFire microprocessor with VxWorks RTOS running the Space **Telecommunications Radio System (STRS) Architecture**
- **CRAM** (Chalcogenide RAM) Memory (4 Mb)
- Analog (10 MHz filter bandwidth) and Digital (6 MHz filter bandwidth) automatic gain controls (AGCs)

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# **Test Objective and Plan**

- Characterize the relationship between:
  - SDR input power
  - SDR baseplate temperature
  - Waveform configuration
  - The digital and analog AGC values
- Temperature range:
  - − -15 to +45 °C
- SDR input power range:
  - -90 to -130 dBm
- Results will be used to estimate SDR input power in future testing
- Testing phases included:
  - GD verification testing
  - GRC thermal vacuum (TVAC) testing
  - GRC verification testing





# **GRC Test Setup**

- S-Band TDRSS Simulator (TSIM) was used to emulate the forward link waveform
- TSIM was connected to the SCaN Testbed using a test equipment interface circuit and RF cable
- SDR input power was measured from a coupled port in the interface circuit using a power meter
- The RF subsystem inside the SCaN Testbed was used to connect an antenna port to the GD SDR
- During TVAC, the RF cable and SCaN Testbed were located in the vacuum chamber



#### **GRC** Test Setup



AGC Characterization Results at Ambient Temperature

#### Analog AGC at 26 °C



- Analog AGC varies with center frequency (MA/SA)
- Digital AGC varies with symbol rate (coding + data rate)

#### Digital AGC at 26 °C



### AGC Characterization Results over Temperature

#### Analog AGC

#### **Digital AGC**



• Both analog and digital AGCs vary over temperature. The analog AGC variation is more significant.



# Sources of Error in Data Collection

- Differences in the GD and GRC test setup (+/-.5 dB)
- Compensation method for the cable loss over temperature during thermal vacuum testing (+/-.5 dB)



- Data interpolated for waveforms with incomplete data sets (+/- 1 dB)
- System loss measurement error (+/-.3 dB)

# SDR Input Power Estimation using Digital AGC







### Estimation of Interferer Signal Strength using Digital AGC





# Recommendations and Forward Work

#### Recommendations

- Plan test phases and design a test setup that can be kept constant throughout each phase
- Balance SDR reconfigurable parameters with project test time

### **Forward Work**

- 3 SDR input power estimation algorithms have been developed
- Characterize the SDR input power algorithms during on-orbit operations on ISS
- Utilize the engineering model (EM) characterization data to create SDR input power estimators for the EM



### **Questions?**

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